

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/713,491	LIU, YAN	
Examiner		Art Unit	2859	Page 1 of 3
Mirells Jagan				

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 57000532 A	01-1982	Japan	TAGAMI, ICHIZO	G01J 03/02
	O	JP 56033518 A	04-1981	Japan	TAGAMI, ICHIZO	G01J 05/60
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Shand et al., "Temperature Dependence of the Excited-State Absorption of Alexandrite", IEEE Journal of Quantum Electronics, Vol. QE-19, No. 3, pp. 480-484, March 1983.
	V	Augousti et al., "A Laser- Pumped Temperature Sensor Using the Fluorescent Decay Time of Alexandrite", Journal of Lightwave Technology", Vol. LT-5, No. 6, pp. 759-762, June 1987.
	W	Alcala et al., "Real Time Frequency Domain Fiberoptic Temperature Sensor", IEEE Transactions on Biomedical Engineering", Vol. 42, No. 5, pp. 471-476, May 1995.
	X	Bukin et al., "Growth of Alexandrite Crystals and Investigation of Their Properties", Journal of Crystal Growth, vol. 52, pp. 537-541 , 1981.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/713,491	LIU, YAN	
Examiner		Art Unit	Mirellys Jagan	
		2859	Page 2 of 3	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Farmer, "Plasma Temperature Measurement", Handbook of Temperature Measurement: Temperature and Humidity Measurement, Vol. 1, pp. 119-131 , 1998.
	V	Liu et al., "The 'Alexandrite Effect' in Gemstones", Color Research & Application, vol. 19, No.3, pp. 186-191, June 1994.
	W	Liu et al., "Relationship Between the Crystallographic Orientation and the 'Alexandrite Effect' in Synthetic Alexandrite", Mineralogical Magazine, vol. 59, pp. 111-114, March 1995.
	X	Liu et al., "Abnormal Hue-angle Change of the Gemstone Tanzanite between CIE Illuminants D65 and A in CIELAB Color Space",Color Research & Application, vol 20, No 4, pp. 245-250, August 1995.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/713,491	LIU, YAN	
Examiner Mirellys Jagan		Art Unit 2859	Page 3 of 3	

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Michalski et al., Temperature Measurement, 2nd ed. Wiley & Sons, pp. 151-228, 2001.
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.